



Product data sheet

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Feature

80W peak pulse power per line (t_P = 8/20μs) SOD-923 package Replacement for MLV(0402) Bidirectional configurations Response time is typically < 1ns Low clamping voltage RoHS compliant Transient protection for data lines to EC61000-4-2(ESD) ±30KV(air), ±30KV(contact); IEC61000-4-4 (EFT) 40A (5/50ns)

Applications

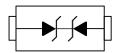
Cellular phones Portable devices Digital cameras Power supplies

Mechanical Characteristics

Lead finish:100% matte Sn(Tin) Mounting position: Any Qualified max reflow temperature:260℃ Device meets MSL 1 requirements Pure tin plating: 7 ~ 17 um Pin flatness:≤3mil

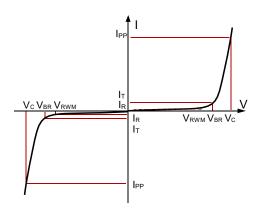
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SOD-923



Electronics Parameter

Symbol	Parameter			
V _{RWM}	Peak Reverse Working Voltage			
I _R	Reverse Leakage Current @ V _{RWM}			
V _{BR}	Breakdown Voltage @ I⊤			
Ι _Τ	Test Current			
IPP	Maximum Reverse Peak Pulse Current			
Vc	Clamping Voltage @ IPP			
P _{PP}	Peak Pulse Power			
CJ	Junction Capacitance			
IF	Forward Current			
VF	Forward Voltage @ I _F			





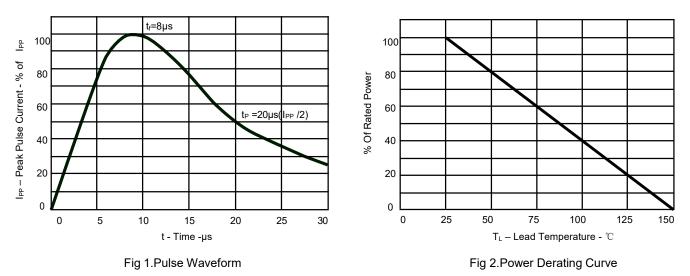
Electrical characteristics per line@25°C (unless otherwise specified)

Parameter	Symbol	Conditions	Min.	Тур.	Max.	Units
Peak Reverse Working Voltage	V _{RWM}				5	V
Breakdown Voltage	V _{BR}	I _t = 1mA	5.6	6.7	7.8	V
Reverse Leakage Current	I _R	V _{RWM} = 5V Т=25℃			1.0	μA
Maximum Reverse Peak Pulse Current	I _{PP}			5		А
Clamping Voltage	Vc	I _{PP} =1A			8	V
Clamping Voltage	Vc	I _{PP} =3A			13	V
Clamping Voltage	Vc	I _{PP} =5A			15	V
Junction Capacitance	Cj	V _R =0V f = 1MHz		12	15	pF

Absolute maximum rating@25℃

Rating	Symbol	Value	Units
Peak Pulse Power (t _p =8/20µs)	P _{pp}	80	W
Operating Temperature	ire T _J		°C
Storage Temperature	Тѕтс	-55 to +150	°C







ESD9B5.0ST5G Semiconductor

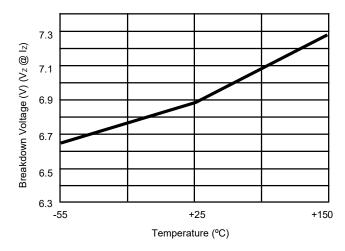


Fig 3.Typical Breakdown Voltage vs. Temperature

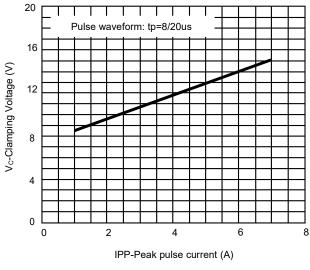


Fig 5. Clamping voltage vs. Peak pulse current

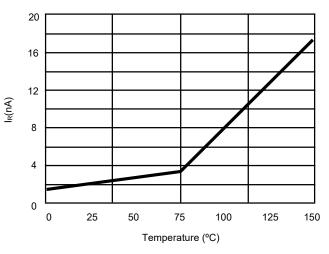


Fig 4. Typical Leakage Current vs. Temperature

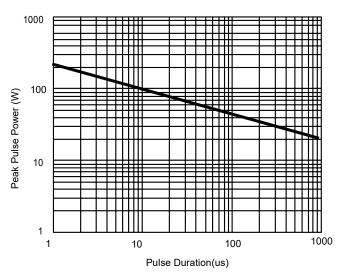
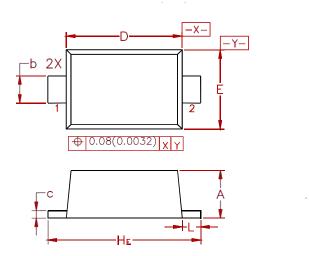


Fig 6. Non-Repetitive Peak Pulse Power vs. Pulse time

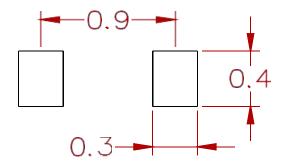


PACKAGE MECHANICAL DATA



Dim	Millimeters			Inches			
	Min	Nom	Max	Min	Nom	Max	
Α	0.36	0.40	0.43	0.014	0.016	0.017	
b	0.15	0.20	0.25	0.006	0.008	0.010	
С	0.07	0.12	0.17	0.003	0.005	0.007	
D	0.75	0.80	0.85	0.030	0.031	0.033	
E	0.55	0.60	0.65	0.022	0.024	0.026	
HE	0.95	1.00	1.05	0.037	0.039	0.041	
L	0.05	0.10	0.15	0.002	0.004	0.006	

Suggested Pad Layout



Dimensions: Millimeters

REEL SPECIFICATION

P/N	PKG	QTY
ESD9B5.0ST5G	SOD-923	8000



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